Supporting Information

Rapid Low Temperature Self-Healable Polymeric composite for Flexible Electronic Devices

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Figure S1: a) and b) ¹H liquid-state NMR spectra of PU-DA/ 50 wt% EMITFS and ionic liquid (EMITFS). c) ¹H solid-state NMR spectra of PU-DA/ 50 wt% EMITFS film, PU-DA film and ionic liquid (EMITFS).



Figure S2: FTIR spectrum of PU-DA, 16.7 wt % EMITFS in PU-DA, 25 wt % EMITFS in PU-DA, 33.3 wt % EMITFS in PU-DA, 41.7 wt % EMITFS in PU-DA, 50 wt % EMITFS in PU-DA, 58.3 wt % EMITFS in PU-DA and EMITFS (IL).



Figure S3: The optical microscopy images of PU-DA and PU-DA/ 50 wt% EMITFS, suggests that EMITFS is be homogeneously mixed within the PU-DA polymer matrix.



Figure S4: TGA curves of PU-DA, 16.7 wt % EMITFS in PU-DA, 25 wt % EMITFS in PU-DA, 33.3 wt % EMITFS in PU-DA, 41.7 wt % EMITFS in PU-DA, 50 wt % EMITFS in PU-DA and 58.3 wt % EMITFS in PU-DA.



Figure S5: DSC curves of 16.7 wt % EMITFS in PU-DA, 25 wt % EMITFS in PU-DA, 33.3 wt % EMITFS in PU-DA, 41.7 wt % EMITFS in PU-DA and 58.3 wt % EMITFS in PU-DA

Composition of EMITFS (%)	Healing Temperature (°C)
0.00 (PU-DA)	120
16.7	90
25.0	80
33.3	70
41.7	70
50.0	60
58.3	60

Table S1: The healing temperatures of the different composition of EMITFS in PU-DA film. All the film was of same thickness ($20 \mu m$) and kept at the required healing temperature according to the composition of EMITFS for 10 mins.



Figure S6: Stress-strain curves of PU-DA, 16.7 wt % EMITFS in PU-DA, 25 wt % EMITFS in PU-DA, 33.3 wt % EMITFS in PU-DA, 41.7 wt % EMITFS in PU-DA, 50 wt % EMITFS in PU-DA and 58.3 wt % EMITFS in PU-DA.



Figure S7: Image of the fracture of the damaged sample (a) and the healed sample (b).



Figure S8: Transmittance spectrum of PU-DA, 16.7 wt % EMITFS in PU-DA, 25 wt % EMITFS in PU-DA, 33.3 wt % EMITFS in PU-DA, 41.7 wt % EMITFS in PU-DA, 50 wt % EMITFS in PU-DA and 58.3 wt % EMITFS in PU-DA. The change in transmittance of 58.3 wt % EMITFS in PU-DA was due to the non-uniformity of the film.



Figure S9: Dielectric constant of PU-DA/EMITFS film with various concentration of EMITFS added: PU-DA, 25 wt % EMITFS in PU-DA, 33.3 wt % EMITFS in PU-DA, 41.7 wt % EMITFS in PU-DA, 50 wt % EMITFS in PU-DA and 58.3 wt % EMITFS in PU-DA.



Figure S10: Spin coated sample of EMITFS in PU-DA. All the samples are coated over glass at 1000 rpm for 20 s. Comparison of Surface Uniformity between PU-DA + 50.0% EMITFS and PU-DA + 58.3% EMITFS.